

CALIBRATION LABORATORIES

NVLAP LAB CODE 105000-0

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

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CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) ^{Notes 1,2}

Measured Parameter or Device Calibrated	Range	Expanded Uncertainty ^{Note 3}	Remarks
DIMENSIONAL			
GAGE BLOCKS (20/D03)			
Steel and Chrome Only ^{Note 7}	< 0.1 in 0.1 in to 1.0 in > 1.0 in to 4.0 in >4.0 in to 20 in	3.0 μin 2.9 μin $(1.9 + 0.9L) \mu\text{in}$ $(5.0 + 0.6L) \mu\text{in}$	Mechanical Comparison
	< 2.6 mm 2.6 mm to 25 mm > 25 mm to 100 mm >100 mm to 500 mm	0.08 μm 0.07 μm $(0.05 + 0.94L) \mu\text{m}$ $(0.13 + 0.47L) \mu\text{m}$	Mechanical Comparison
LENGTH and DIAMETER; STEP GAGES (20/D05)			
Length ^{Note 7}	0 m to 1.2 m	$(0.31 + 0.40L) \mu\text{m}$	Moore M48 CMM
LINE STANDARDS (20/D06)			
Line Standards ^{Note 8}	0 mm to 600 mm	$(0.54 + 1.9L) \mu\text{m}$	CMM (optical)
OPTICAL REFERENCE PLANES (20/D08)			
Glass Reticles, Stage Micrometer, Glass Magnification Scales and Calibration Charts	0.56 x 0.43 mm	1.5 μm	CMM (optical), Measurements taken within camera field-of-view

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CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) ^{Notes 1,2}

Measured Parameter or Device Calibrated	Range	Expanded Uncertainty ^{Note 3}	Remarks
Optical Grid Plates/Reference Planes ^{Note 8}	0 mm to 848 mm	(0.82 + 1.8L) μ m	CMM (optical)
ROUNDNESS (20/D09)			
Roundness	4.0 mm to 152.4 mm	0.013 μ m	Roundness Instrument
SPHERICAL DIAMETER; PLUG / RING GAGES (20/D11) ^{Note 7}			
Spherical Diameter	≤ 4 in	16 μ m	Bench micrometer
Cylindrical Diameter	≤ 1 in	14 μ m	
Ring Gages (inside diam) ^{Note 8}	to 0.91 m	(0.25 + 1.1L) μ m	Moore M48 CMM; 36 in
SURFACE TEXTURE (20/D12)			
Ra (Roughness Average)	41 μ m to 120 μ m (1.04 μ m to 3.05 μ m) 13 μ m to 40 μ m (0.33 μ m to 1.02 μ m) 12 μ m (0.31 μ m)	2.6 μ m (0.065 μ m) 1.1 μ m (0.027 μ m) 0.053 μ m (0.014 μ m)	Contact Profilometer
TWO DIMENSIONAL GAGES (20/D15)			
Diagonal ^{Note 7}	0 m to 1.3 m	(0.36 + 1.7L) μ m	Moore M48 CMM
COORDINATE MEASUREING MACHINES (20/D16)			
Diagonal (3D) ^{Note 7}	0 m to 1.4 m	(0.61 + 2.6L) μ m	Spatial Moore M48 CMM
GEARS (20/D18)			
Involute Profile	to 14 in diameter	(0.47 + 3.08L) μ m	CMM
Infinite Lead/Helix	to 6 in diameter	0.80 μ m	CMM
99 in Lead/Helix	to 6 in diameter	0.90 μ m	
32 in Lead/Helix	to 6 in diameter	1.1 μ m	
16 in Lead/Helix LH	to 6 in diameter	1.2 μ m	
16 in Lead/Helix RH	to 6 in diameter	1.2 μ m	
11 in Lead/Helix	to 6 in diameter	1.3 μ m	
Pin/Journal diameter	to 6 in diameter	0.50 μ m	CMM
Pin/Journal roundness	to 4 in diameter	0.025 μ m	Roundness Instrument
Index and Runout	to 24 in	3.3 μ m	CMM with rotary table

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CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or Device Calibrated	Range	Frequency Range	Expanded Uncertainty Notes 3, 5	Remarks
ELECTROMAGNETICS – DC/LOW FREQUENCY				
AC RESISTORS and CURRENT (20/E02)				
AC Current Source	0 μ A to 220 μ A	10 Hz to 20 Hz > 20 Hz to 40 Hz > 40 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	0.025 % + 16 nA 0.016 % + 10 nA 0.012 % + 8 nA 0.02 % + 12 nA 0.11 % + 65 nA	Fluke 5720A
	> 220 μ A to 2.2 mA	10 Hz to 20 Hz > 20 Hz to 40 Hz > 40 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	0.025 % + 42 nA 0.016 % + 37 nA 0.012 % + 37 nA 0.02 % + 0.11 μ A 0.11 % + 0.65 μ A	
	> 2.2 mA to 22 mA	10 Hz to 20 Hz > 20 Hz to 40 Hz > 40 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	0.025 % + 0.40 μ A 0.016 % + 0.35 μ A 0.012 % + 0.35 μ A 0.02 % + 0.56 μ A 0.11 % + 5 μ A	
	> 22 mA to 220 mA	10 Hz to 20 Hz > 20 Hz to 40 Hz > 40 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	0.025 % + 4.2 μ A 0.016 % + 3.7 μ A 0.012 % + 2.8 μ A 0.02 % + 3.7 μ A 0.11 % + 10.1 μ A	
	> 220 mA to 2.2 A	20 Hz to 1kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	0.027 % + 37 μ A 0.045 % + 81 μ A 0.70 % + 0.16 mA	
AC Current Measure	0 μ A to 200 μ A	10 Hz to 300 Hz > 300 Hz to 1 kHz > 1 kHz to 10 kHz	0.03 % + 20 nA 0.03 % + 20 nA 0.03 % + 20 nA	Fluke 8508A

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Measured Parameter or Device Calibrated	Range	Frequency Range	Expanded Uncertainty Notes 3, 5	Remarks
	> 200 μ A to 2 mA	10 Hz to 300 Hz > 300 Hz to 1 kHz > 1 kHz to 10 kHz	0.03 % + 0.20 μ A 0.03 % + 0.20 μ A 0.03 % + 0.20 μ A	
	> 2 mA to 20 mA	10 Hz to 300 Hz > 300 Hz to 1 kHz > 1 kHz to 10 kHz	0.03 % + 2.0 μ A 0.03 % + 2.0 μ A 0.03 % + 2.0 μ A	
	> 20 mA to 200 mA	10 Hz to 300 Hz > 300 Hz to 1 kHz > 1 kHz to 10 kHz	0.032 % + 20 μ A 0.029 % + 20 μ A 0.029 % + 20 μ A	
	> 200 mA to 2 A	10 Hz to 2 kHz > 2 kHz to 10 kHz	0.073 % + 0.20 mA 0.087 % + 0.20 mA	
	> 2 A to 20 A	> 10 Hz to 2 kHz > 2 kHz to 10 kHz	0.21 % + 2.0 mA 0.31 % + 2.0 mA	

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or Device Calibrated	Range	Expanded Uncertainty Notes 3, 5	Remarks
DC RESISTANCE and CURRENT (20/E05)			
DC Resistance Fixed Points (Shunts in air)	20 $\mu\Omega$ (to 1 000 A)	0.010 %	L&N 4372 Shunt
(Shunts in air)	0.001 Ω (to 500 A)	0.030 %	L&N 4364 Shunts
	0.01 Ω (to 100A)	0.010 %	L&N 4361 Shunts
	0.1 Ω (to 15 A)	0.010%	L&N 4360 Shunts
DC Resistance Fixed Points (in air)	1 Ω	4.6 $\mu\Omega/\Omega$	Fluke 742A-1
	10 Ω	3.4 $\mu\Omega/\Omega$	Fluke 742A-10
	100 Ω	4.4 $\mu\Omega/\Omega$	Fluke 742A-100
	1 k Ω	5.3 $\mu\Omega/\Omega$	Fluke 742A-1k
	10 k Ω	3.8 $\mu\Omega/\Omega$	Fluke 742A-10k
	100 k Ω	5.2 $\mu\Omega/\Omega$	Fluke 742A-100k
	1 M Ω	6.2 $\mu\Omega/\Omega$	Fluke 742A-1M
	10 M Ω	6.6 $\mu\Omega/\Omega$	Fluke 742A-10M

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CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or Device Calibrated	Range	Expanded Uncertainty Notes 3, 5	Remarks
DC Resistance Source	1.9 Ω 19 Ω 190 Ω 1.9 k Ω 19 k Ω 190 k Ω 1.9 M Ω 19 M Ω 100 M Ω	96 $\mu\Omega/\Omega$ 118 $\mu\Omega/\Omega$ 81 $\mu\Omega/\Omega$ 14 $\mu\Omega/\Omega$ 116 $\mu\Omega/\Omega$ 37 $\mu\Omega/\Omega$ 24 $\mu\Omega/\Omega$ 127 $\mu\Omega/\Omega$ 496 $\mu\Omega/\Omega$	Fluke 5720A
DC Resistance Measure	0 Ω to 2 Ω > 2 Ω to 20 Ω > 20 Ω to 200 Ω > 200 Ω to 2 k Ω > 2 k Ω to 20 k Ω > 20k Ω to 200 k Ω > 200 k Ω to 2 M Ω > 2 M Ω to 20 M Ω > 20 M Ω to 200 M Ω > 200 M Ω to 2 G Ω	18 $\mu\Omega/\Omega$ + 4 $\mu\Omega$ 11 $\mu\Omega/\Omega$ + 14 $\mu\Omega$ 81 $\mu\Omega/\Omega$ + 5.1 $\mu\Omega$ 9 $\mu\Omega/\Omega$ + 0.5 m Ω 9 $\mu\Omega/\Omega$ + 5 m Ω 37 $\mu\Omega/\Omega$ + 50 m Ω 10 $\mu\Omega/\Omega$ + 1.0 Ω 33 $\mu\Omega/\Omega$ + 0.2 k Ω 0.054 % + 0.01 M Ω 0.15 % + 1 M Ω	Fluke 8508A
DC Current Source	0 μ A to 220 μ A > 220 μ A to 2.2 mA > 2.2 mA to 22 mA > 22 mA to 220 mA > 220 mA to 2.2 A > 2.2 A to 11 A > 11 A to 100 A	40 μ A/A + 6 nA 35 μ A/A + 7 nA 35 μ A/A + 40 nA 45 μ A/A + 4 μ A 88 μ A/A + 12 μ A 0.037 % + 0.48 mA 0.032 %	Fluke 5720A Fluke 5725A Amplifier Valhalla 2555A
DC Current Measure	0 μ A to 200 μ A > 200 μ A to 2 mA > 2 mA to 20 mA > 20 mA to 200 mA > 200 mA to 2 A > 2 A to 20 A > 20 A to 1000 A	13 μ A/A + 0.40 nA 13 μ A/A + 4.0 nA 15 μ A/A + 42 nA 48 μ A/A + 0.8 μ A 0.019 % + 16 μ A 0.053 % + 12 mA 0.010%	Fluke 8508A L&N/ Rubicon Shunts

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Measured Parameter or Device Calibrated	Range	Expanded Uncertainty Notes 3, 5	Remarks
DC Current Source/Measure (Calibration of DC Shunts)	10 $\mu\Omega$ to 100 m Ω	0.010 %	Comparison to DC Shunts at Source Current 0.15 A to 1000 A
DC VOLTAGE (20/E06)			
DC Voltage Source	0 mV to 220 mV > 220 mV to 2.2 V > 2.2 V to 11 V > 2.2 V to 22 V > 22 V to 220 V > 220 V to 1100 V	7.5 $\mu\text{V/V} + 0.40 \mu\text{V}$ 5.1 $\mu\text{V/V} + 0.70 \mu\text{V}$ 3.7 $\mu\text{V/V} + 2.5 \mu\text{V}$ 4.0 $\mu\text{V/V} + 4 \mu\text{V}$ 30.6 $\mu\text{V/V} + 40 \mu\text{V}$ 221.3 $\mu\text{V/V} + 400 \mu\text{V}$	Fluke 5720A
DC Voltage Measure	0 V to 200 mV > 200 mV to 2 V > 2 V to 20 V > 20 V to 200 V > 200 V to 1000 V	5.5 $\mu\text{V/V} + 0.5 \mu\text{V}$ 3.9 $\mu\text{V/V} + 0.2 \mu\text{V}$ 4.1 $\mu\text{V/V} + 1.0 \mu\text{V}$ 30.7 $\mu\text{V/V} + 12 \mu\text{V}$ 221.3 $\mu\text{V/V} + 0.12 \text{ mV}$	Fluke 8508A

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or Device Calibrated	Range	Frequency Range	Expanded Uncertainty Notes 3, 5	Remarks
LF AC VOLTAGE (20/E09)				
LF AC Voltage Source	0 mV to 2.2 mV	40 Hz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 300 kHz > 300 kHz to 500 kHz > 500 kHz to 1 MHz	0.008 % + 4.2 μV 0.02 % + 4.2 μV 0.063 % + 5.1 μV 0.11 % + 10.1 μV 0.14 % + 20 μV 0.27 % + 20 μV	Fluke 5720A
	> 2.2 mV to 22 mV	40 Hz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 300 kHz > 300 kHz to 500 kHz > 500 kHz to 1 MHz	0.008% + 12 μV 0.02 % + 12 μV 0.05 % + 13 μV 0.11 % + 15 μV 0.14 % + 23 μV 0.27 % + 23 μV	

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Measured Parameter or Device Calibrated	Range	Frequency Range	Expanded Uncertainty Notes 3, 5	Remarks
	> 22 mV to 220 mV	40 Hz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 300 kHz > 300 kHz to 500 kHz > 500 kHz to 1 MHz	0.008 % + 7.0 µV 0.02 % + 7.0 µV 0.05 % + 17 µV 0.09 % + 20 µV 0.14 % + 25 µV 0.27 % + 45 µV	
	> 220 mV to 2.2 V	40 Hz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 300 kHz > 300 kHz to 500 kHz > 500 kHz to 1 MHz	45 µV/V + 8.1 µV 75 µV/V + 10 µV 0.011 % + 30 µV 0.042 % + 80 µV 0.1 % + 0.20 mV 0.17 % + 0.30 mV	
	> 2.2 V to 22 V	40 Hz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 300 kHz > 300 kHz to 500 kHz > 500 kHz to 1 MHz	73 µV/V + 51 µV 88 µV/V + 0.10 mV 0.011 % + 0.20 mV 0.028 % + 0.60 mV 0.1 % + 2.0 mV 0.15 % + 3.2 mV	
	> 22 V to 220 V	40 Hz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz	0.087 % + 0.61 mV 0.045 % + 1.0 mV 0.072 % + 2.5 mV	
	> 220 V to 1000 V	40 Hz to 1 kHz	.09 % + 3.5 mV	
	220 V to 600 V	40 Hz to 1 kHz > 1 to 20 kHz > 20 to 30 kHz > 30 to 50 kHz > 50 to 100 kHz	0.03 % + 4.2 mV 0.036 % + 6.1 mV 0.068 % + 11.1 mV 0.074 % + 11.1 mV 0.24 % + 45 mV	Fluke 5720A/5725A
	> 600 V to 1100 V	40 Hz to 1 kHz > 1 to 20 kHz > 20 to 30 kHz	0.039 % + 4.2 mV 0.065 % + 6.1 mV 0.087 % + 11.1 mV	

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Measured Parameter or Device Calibrated	Range	Frequency Range	Expanded Uncertainty ^{Notes 3, 5}	Remarks
LF AC Voltage Measure	0 V to 200 mV	10 Hz to 100 Hz	0.015 % + 4.0 μ V	Fluke 8508A
		> 100 Hz to 2 kHz	0.012 % + 2.0 μ V	
		> 2 kHz to 10 kHz	0.014 % + 4.0 μ V	
		> 10 kHz to 30 kHz	0.034 % + 8.0 μ V	
		> 30 kHz to 100 kHz	0.077 % + 20 μ V	
	> 0.2 V to 2 V	10 Hz to 100 Hz	0.012 % + 20 μ V	
		> 100 Hz to 2 kHz	81 μ V/V + 20 μ V	
		> 2 kHz to 10 kHz	0.011 % + 20 μ V	
		> 10 kHz to 30 kHz	0.022 % + 40 μ V	
		> 30 kHz to 100 kHz	0.058 % + 0.20 mV	
		> 100 kHz to 300 kHz	0.30 % + 2.3 mV	
	> 2 V to 20 V	> 300 kHz to 1 MHz	1.0 % + 20 mV	
		10 Hz to 100 Hz	0.014 + 0.20 mV	
		> 100 Hz to 2 kHz	0.009 + 0.20 mV	
		> 2 kHz to 10 kHz	0.012 % + 0.20 mV	
		> 10 kHz to 30 kHz	0.022 % + 0.40 mV	
		> 30 kHz to 100 kHz	0.058 % + 2.0 mV	
	> 20 V to 200 V	> 100 kHz to 300 kHz	0.30 % + 20 mV	
		> 300 kHz to 1 MHz	1.0 % + 0.20 V	
		10 Hz to 100 Hz	0.14 % + 2.0 mV	
		> 100 Hz to 2 kHz	0.037 % + 2.0 mV	
		> 2 kHz to 10 kHz	0.035 % + 2.0 mV	
		> 10 kHz to 30 kHz	0.043 % + 4.0 mV	
	> 200 V to 1000 V	> 30 kHz to 100 kHz	0.091 % + 20 mV	
		40 kHz to 10 kHz	0.024 % + 1.2 mV	
		> 10 kHz to 30 kHz	0.07 % + 1.2 mV	

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Measured Parameter or Device Calibrated	Range	Expanded Uncertainty ^{Notes 3,5}	Remarks
TIME and FREQUENCY			
FREQUENCY DISSEMINATION (20/F01)			
Frequency Measure	1 MHz 5 MHz 10 MHz	1 x 10 ⁻¹² Hz/Hz 1 x 10 ⁻¹² Hz/Hz 1 x 10 ⁻¹² Hz/Hz	NIST FMAS + Fluke 910R
MECHANICAL			
MASS DETERMINATION (20/M08)			
Mass ^{Note 4}	25 kg 20 kg 10 kg 5 kg 2 kg 1 kg 500 g 200 g 100 g 50 g 20 g 10 g 5 g 2 g 1 g 500 mg 200 mg 100 mg 50 mg 20 mg 10 mg 5 mg 2 mg 1 mg	30 mg 27.6 mg 15.9 mg 6.6 mg 2.5 mg 0.86 mg 0.35 mg 0.22 mg 0.12 mg 43 µg 18 µg 12 µg 14 µg 8.4 µg 7.9 µg 3.3 µg 2.5 µg 3.0 µg 2.2 µg 1.9 µg 2.4 µg 4.5 µg 4.2 µg 1.7 µg	Echelon II

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CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or Device Calibrated	Range	Expanded Uncertainty Notes 3,5	Remarks
TORQUE (20/M15)			
Torque Measure	5 lb-in to 50 lb-in	0.33 %	TTC 400 Torque Calibrator
	30 lb-in to 400 lb-in	0.26 %	
	80 lb-in to 1000 lb-in	0.22 %	
	20 lbf to 250 lbf	0.25 %	

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or Device Calibrated	Test Load Range	Readability	Expanded Uncertainty Note 3	Remarks
CALIBRATION OF WEIGHING INSTRUMENTS (20/M16)				
Balances	30 kg	1 g	1.3 g	
Field calibrations available ^{Note 4}	20 kg	0.1 g	0.13 g	
	10 kg	0.01 g	12 mg	
	1 kg	1 mg	1.3 mg	
	100 g	0.1 mg	0.13 mg	
	10 g	0.01 mg	0.13 mg	
	1 g	0.001 mg	0.0016 mg	

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or Device Calibrated	Range	Expanded Uncertainty Notes 3, 5	Remarks
THERMODYNAMIC			
LABORATORY THERMOMETERS, DIGITAL and ANALOG (20/T03)			
Temperature Measuring Devices ^{Note 4}	-90 °C to 0 °C	0.0034 °C	Ametek HTC 125A Dry Well w/SPRT and 1594A Super Thermometer
	0 °C to 30 °C	0.0024 °C	7012 Liquid Bath w./SPRT and Super Thermometer
	0 °C to 125 °C	0.0043 °C	Ametek HTC 125A Dry Well w/SPRT and Super Thermometer

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Measured Parameter or Device Calibrated	Range	Expanded Uncertainty Notes 3, 5	Remarks
	126 °C to 420 °C	0.015 °C	9173 Dry Well w/SPRT and Super Thermometer
	421 °C to 700 °C	0.059 °C	9173 Dry Well w/ 5624 PRT
	701 °C to 1000 °C	0.22 °C	9112 Tube Furnace w/ 5624 PRT
LEAK ARTIFACTS (20/T04)			
Leak Artifacts	1.0 X 10 ⁻⁴ atm cc/sec to 9.9 X 10 ⁻⁴ atm cc/sec 1.0 X 10 ⁻⁵ atm cc/sec to 9.9 X 10 ⁻⁵ atm cc/sec 1.0 X 10 ⁻⁶ atm cc/sec to 9.9 X 10 ⁻⁶ atm cc/sec 7.0 X 10 ⁻⁷ atm cc/sec to 9.9 X 10 ⁻⁷ atm cc/sec 5.0 X 10 ⁻⁷ atm cc/sec to 6.9 X 10 ⁻⁷ atm cc/sec 3.0 X 10 ⁻⁷ atm cc/sec to 4.9 X 10 ⁻⁷ atm cc/sec	6.4 % 4.2 % 4.4 % 4.5 % 5.3 % 5.6 %	Vacuum Decay Method
PRESSURE (20/T05)			
Pneumatic Deadweight Piston Gauge (Absolute & Gauge Mode)	1.3 psi to 23.73 psi (9.0 kPa to 164 kPa) 23.73 psi to 95.96 psi (164 kPa to 662 kPa) 95.96 psia to 1002.91 psia (662 kPa to 6915 kPa)	0.0024 % 0.0017 % 0.0018 %	Direct Pressure Comparison Nitrogen
Hydraulic Deadweight Piston Gauge (Gauge Mode)	208.65 psig to 3 712.41 psig (1.4 MPa to 25.6 MPa)	0.0062 %	Direct Comparison Oil

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Hydraulic Deadweight Piston Gauge (Gauge Mode)	19 882.35 psig to 39 645.51 psig	0.0065%	Direct Comparison Nitrogen
	208.65 psig to 3712.41 psig (1.4 MPa to 25.6 MPa)	0.0045 %	
	3712.41 psig to 15 000 psig (25.6 MPa to 103.5 MPa)	0.0065 %	
VACUUM and LOW PRESSURE TRANSDUCERS (20/T10)			
Capacitance Diaphragm Gauge	0.001 Torr to 0.004 Torr 0.004 Torr to 0.01 Torr 0.01 Torr to 1.0 Torr 1.0 Torr to 10 Torr 10 Torr to 100 Torr 100 Torr to 1000 Torr	(where x is the applied pressure) (0.0035x ^{-0.949}) % 0.64 % 0.43 % 0.090 % 0.29 % 0.085 %	Direct Comparison; MKS Baratron, 1 Torr MKS Baratron 10 Torr MKS Baratron, 100 Torr MKS Baratron, 1000 Torr
Ionization Gauge	1.0 X 10 ⁻⁴ Torr to 1.0 X 10 ⁻⁶ Torr 1.0 X 10 ⁻⁶ Torr to 1.0 X 10 ⁻⁷ Torr 1.0 X 10 ⁻⁷ Torr to 1.0 X 10 ⁻⁸ Torr 1.0 X 10 ⁻⁸ Torr to 1.0 X 10 ⁻⁹ Torr	5.9 % 4.0 % 4.3 % 5.4 %	Direct Comparison; Granville-Phillips 370121
Spinning Rotor Gauge	1.0 X 10 ⁻⁴ Torr to 1.0 X 10 ⁻⁷ Torr	Greater of (1% or 8.07E-07x)	Direct Comparison; MKS SRG-2CE
END			

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Notes

Note 1: A Calibration and Measurement Capability (CMC) is a description of the best result of a calibration or measurement (result with the smallest uncertainty of measurement) that is available to the laboratory's customers under normal conditions, when performing more or less routine calibrations of nearly ideal measurement standards or instruments. The CMC is described in the laboratory's scope of accreditation by: the measurement parameter/device being calibrated, the measurement range, the uncertainty associated with that range (see note 3), and remarks on additional parameters, if applicable.

Note 2: Calibration and Measurement Capabilities are traceable to the national measurement standards of the U.S. or to the national measurement standards of other countries and are thus traceable to the internationally accepted representation of the appropriate SI (Système International) unit.

Note 3: The uncertainty associated with a measurement in a CMC is an expanded uncertainty with a level of confidence of approximately 95 %, typically using a coverage factor of $k = 2$. However, laboratories may report a coverage factor different than $k = 2$ to achieve the 95 % level of confidence. Units for the measurand and its uncertainty are to match. Exceptions to this occur when marketplace practice employs mixed units, such as when the artifact to be measured is labeled in non-SI units and the uncertainty is given in SI units (Example: 5 lb weight with uncertainty given in mg).

Note 3a: The uncertainty of a specific calibration by the laboratory may be greater than the uncertainty in the CMC due to the condition and behavior of the customer's device and specific circumstances of the calibration. The uncertainties quoted do not include possible effects on the calibrated device of transportation, long term stability, or intended use.

Note 3b: As the CMC represents the best measurement results achievable under normal conditions, the accredited calibration laboratory shall not report smaller uncertainty of measurement than that given in a CMC for calibrations or measurements covered by that CMC.

Note 3c: As described in Note 1, CMCs cover calibrations and measurements that are available to the laboratory's customers under *normal conditions*. However, the laboratory may have the capability to offer special tests, employing special conditions, which yield calibration or measurement results with lower uncertainties. Such special tests are not covered by the CMCs and are outside the laboratory's scope of accreditation. In this case, NVLAP requirements for the labeling, on calibration reports, of results outside the laboratory's scope of accreditation apply. These requirements are set out in Annex A.5 of NIST Handbook 150, Procedures and General Requirements.

Note 4: Uncertainties associated with field service calibration may be greater as they incorporate on-site environmental contributions, transportation effects, or other factors that affect the measurements. (This note applies only if marked in the body of the scope.)

Note 5: Values listed with percent (%) are percent of reading or generated value unless otherwise noted.

Note 6: NVLAP accreditation is the formal recognition of specific calibration capabilities. Neither NVLAP nor NIST guarantee the accuracy of individual calibrations made by accredited laboratories.

Note 7: L is length in same units as measurand (units shown in Range column).

Note 8: L is length in meters

2022-08-09 through 2023-03-31

Effective dates



For the National Voluntary Laboratory Accreditation Program